A NOTE ON THE SEQUENTIAL t-TEST1

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The purpose of this note is to show how the results and methods of [2] can be used to deduce the asymptotic behavior of the expected sample size for the sequential t-test as the bounds get large. Implicit in this deduction is a proof that the expected sample size is finite, a result also obtained by Ifram [1] who uses somewhat different methods.

We shall only consider the one-sided sequential t-test of $H_0: \mu = 0$, $\sigma > 0$ against $H_1: \mu = \sigma, \sigma > 0$. It is easy to see that the same ideas will work when the alternative hypothesis is $\mu = \delta \sigma$ where δ is some positive number and also if the alternative hypothesis is $|\mu| = \delta \sigma$. We define the sequential t-test with bounds A, A^{-1} (we choose symmetric bounds for convenience) for the problem under consideration as follows: Put $f_{\sigma}(x_1, \dots, x_n) = (1/\sigma^n) \exp\{-(1/\sigma^2) \sum_{1}^{n} (x_i - \sigma)^2\}$, $g_{\sigma}(x_1, \dots, x_n) = (1/\sigma^n) \exp\{-(1/2\sigma^2) \sum_{1}^{n} x_i^2\}$. Take an (n+1)th observation if

(1)
$$\int_0^\infty f_\sigma(x_1, \dots, x_n) (d\sigma/\sigma) < A \int_0^\infty g_\sigma(x_1, \dots, x_n) (d\sigma/\sigma)$$

and if

(2)
$$\int_0^\infty f_{\sigma}(x_1, \dots, x_n)(d\sigma/\sigma) > A^{-1} \int_0^\infty g_{\sigma}(x_1, \dots, x_n)(d\sigma/\sigma),$$

stop and accept H_0 if (2) is violated, and stop and accept H_1 if (1) is violated. The similarities between this procedure and those discussed in [2] (see, in particular, Section 2 of [2]) are obvious; the only difference is that the *a priori* distribution in this case has infinite variation and it is this difference which prevents us from drawing the desired conclusions immediately.

Let N be the number of observations required by this sequential t-test to terminate. We shall concern ourselves with EN when $\mu = 1$, $\sigma = 1$ and we will show that $EN \sim \log A/(\frac{1}{2}\log 2)$ as $A \to \infty$; the dependence of the distribution of N only on μ/σ then will yield the same asymptotic value for EN for any μ , σ with $\mu = \sigma$ i.e. for any point in H_1 . We obtain the asymptotic value of EN by relating the sequential t-test to one of the kind considered in [2]. To accomplish this we first show that there exists $\epsilon > 0$ and $0 < \alpha < 1$ such that

(3)
$$C_n = \frac{\int_0^a g_{\sigma}(x_1, \dots, x_n) (d\sigma/\sigma) + \int_{1/a}^{\infty} g_{\sigma}(x_1, \dots, x_n) (d\sigma/\sigma)}{\int_a^{1/a} g_{\sigma}(x_1, \dots, x_n) (d\sigma/\sigma)} \le 1$$

whenever $2 - \epsilon \leq \sum_{i=1}^{n} x_{i}^{2}/n \leq 2 + \epsilon$, and such that

(4)
$$D_{n} = \frac{\int_{0}^{a} f_{\sigma}(x_{1}, \dots, x_{n}) (d\sigma/\sigma) + \int_{1/a}^{\infty} f_{\sigma}(x_{1}, \dots, x_{n}) (d\sigma/\sigma)}{\int_{a}^{1/a} f_{\sigma}(x_{1}, \dots, x_{n}) (d\sigma/\sigma)} \leq 1$$

Received 26 February 1965.

¹ Research sponsored by NSF Grant G24500.

whenever $2 - \epsilon \le \sum_{i=1}^{n} x_i^2/n \le 2 + \epsilon$ and $1 - \epsilon \le \sum_{i=1}^{n} x_i/n \le 1 + \epsilon$. To see that (3) is so put $V_{n_i} = \sum_{i=1}^{n} x_i^2/n$ and note that

$$\int_0^a g_{\sigma}(x_1, \dots, x_n) (d\sigma/\sigma) \le \max_{0 \le \sigma \le a} (1/\sigma^{n+1}) \exp\left[-(1/2\sigma^2)V_n\right] \int_0^a d\sigma$$

$$= (1/a^n) \exp\left[-(1/2a^2)V_n\right] = K_n \quad (\text{say})$$

whenever $a \leq V_n/(n+1)$;

$$\int_{1/a}^{\infty} g_{\sigma}(x_{1}, \dots, x_{n}) (d\sigma/\sigma) \leq \max_{\sigma \geq 1/a} (1/\sigma^{n-1}) \exp \left[-(1/2\sigma^{2})V_{n}\right] \int_{1/a}^{\infty} (d\sigma/\sigma^{2})$$

$$= a^{n} \exp \left(-\frac{1}{2}a^{2}V_{n}\right) = L_{n} \quad (\text{say})$$

whenever $1/a \ge V_n/(n-1)$;

$$\int_b^c g_{\sigma}(x_1, \cdots, x_n) (d\sigma/\sigma)$$

$$\geq \min \{(1/b^n) \exp [-(1/2b^2)V_n], (1/c^n) \exp [-(1/2c^2)V_n]\} \log (c/b)$$

whenever $b \leq V_n/n \leq c$. By choosing $b = 2 - \epsilon$, $c = 2 + \epsilon$, and a sufficiently close to 0 it is easy to see that (3) is satisfied. Similar tactics work in establishing (4) where the extra condition on $\sum_{i=1}^{n} x_i/n$ is needed.

Let N_1 be the first time that (1) is violated. Then $N \leq N_1$. Let ν_a be the first n such that

$$\int_a^{1/a} f_{\sigma}(d\sigma/\sigma) > A \int_0^{\infty} g_{\sigma}(d\sigma/\sigma) = A \int_a^{1/a} g_{\sigma}(d\sigma/\sigma) \{1 + C_n\}.$$

Then $N_1 \leq \nu_a$. Let M_a be the first n such that

$$\int_a^{1/a} f_\sigma(d\sigma/\sigma) > 2A \int_a^{1/a} g_\sigma(d\sigma/\sigma)$$

and let T be the last time $\sum_{i=1}^{n} X_{i}^{2}/n > 2 + \epsilon$ or $\sum_{i=1}^{n} X_{i}^{2}/n < 2 - \epsilon$. If a and ϵ are chosen so that (3) holds then from

$$P\{\nu_{a} \ge k\} \le P\{T \ge k\} + P\{T < k, \nu_{a} \ge k\}$$

$$\le P\{T \ge k\} + P\{T < k, M_{a} \ge k\}$$

$$\le P\{T \ge k\} + P\{M_{a} \ge k\}$$

we conclude that

$$(5) EN \leq E\nu_a \leq ET + EM_a.$$

When $\mu = 1$, $\sigma = 1$ so that $EX_1^2 = 2$, it is known that $ET < \infty$ (see for example Theorem D in the Appendix of [2]) and does not depend on A. To obtain an upper bound on M_a we can cite the result of Lemma 2 in [2] (the a priori distribution which is relevant is the one with density $1/\sigma 2 |\log a|$ for $a \le \sigma \le 1/a$ and 0 elsewhere, and we replace the c of [2] by 1/2A) which yields

(6)
$$EM_a \leq [1 + o(1)] \log 2A / \inf_{\sigma > 0} E_{\mu=1,\sigma=1} \log [f_1(X_1)/g_{\sigma}(X_1)]$$
$$= [1 + o(1)] \log 2A / \frac{1}{2} \log 2$$

where the o(1) term goes to 0 as $A \to \infty$. (5) and (6) yield

(7)
$$\lim \sup_{A \to \infty} (EN/\log A) \le 2/\log 2.$$

To obtain a bound in the other direction let ν_a be the first n such that

$$A^{-1} \int_{a}^{1/a} g_{\sigma}(d\sigma/\sigma) \{1 + C_{n}\} < \int_{a}^{1/a} f_{\sigma}(d\sigma/\sigma) \{1 + D_{n}\} < A \int_{a}^{1/a} g_{\sigma}(d\sigma/\sigma)$$

is violated; let M_a be the first n such that

$$2A^{-1}\int_a^{1/a}g_\sigma(d\sigma/\sigma) < \int_a^{1/a}f_\sigma(d\sigma/\sigma) < \frac{1}{2}A\int_a^{1/a}g_\sigma(d\sigma/\sigma)$$

is violated; and let T' be the smallest integer m such that $2 - \epsilon < \sum_{1}^{n} X_{i}^{2}/n < 2 + \epsilon$ and $1 - \epsilon < \sum_{1}^{n} X_{i}/n < 1 + \epsilon$ for all $n \ge m$. Then, by use of (3) and (4), $M_{a'} \le \max(\nu_{a'}, T')$ so that $EN \ge E\nu_{a'} \ge EM_{a'} - ET'$. ET' is finite and independent of A (see Theorem D in the Appendix of [2]) so that using the Corollary to Theorem 1 in [2] we obtain

(8)
$$\lim \inf_{A \to \infty} (EN/\log A) \ge 2/\log 2.$$

(7) and (8) then yield

$$\lim_{A\to\infty} (EN/\log A) = 2/\log 2$$

all μ , σ in H_1 . The same result also holds when $\mu = 0$.

REMARKS. 1. Some further computation can be made which will show that $Ee^{tN} < \infty$ for t in some neighborhood of 0. In particular, it isn't too hard to show that $P\{T \ge k\} \le \rho^k$ for some $0 < \rho < 1$ and inspection of the proof of Lemma 2 of [2] and some additional computation will yield $P\{M_a \ge k\} \le \alpha^k$ for some $0 < \alpha < 1$.

- 2. An upper bound for EN when $\mu/\sigma \neq 0$ or 1 can be obtained from the above except when $\mu/\sigma = \frac{1}{2}$ in which case we are unable to make the computation but we are led to believe that the same phenomenon occurs as discussed in Sections 3 and 4 of [2], namely, that the sequential t-test has bad asymptotic properties when $\mu/\sigma = \frac{1}{2}$ and that a modification of the test as discussed for related tests in [2] would be in order.
- 3. When $\mu/\sigma = 0$ or 1 it can be shown along the lines of the argument leading to Theorem 2 of [2] that the probability of error is $o(\log A/A)$. We are unable to verify whether $o(\log A/A)$ can be replaced by $O(A^{-1})$.

REFERENCES

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